

Asymptotics of diffraction corrections in radiometry

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Presentation Outline:

Background

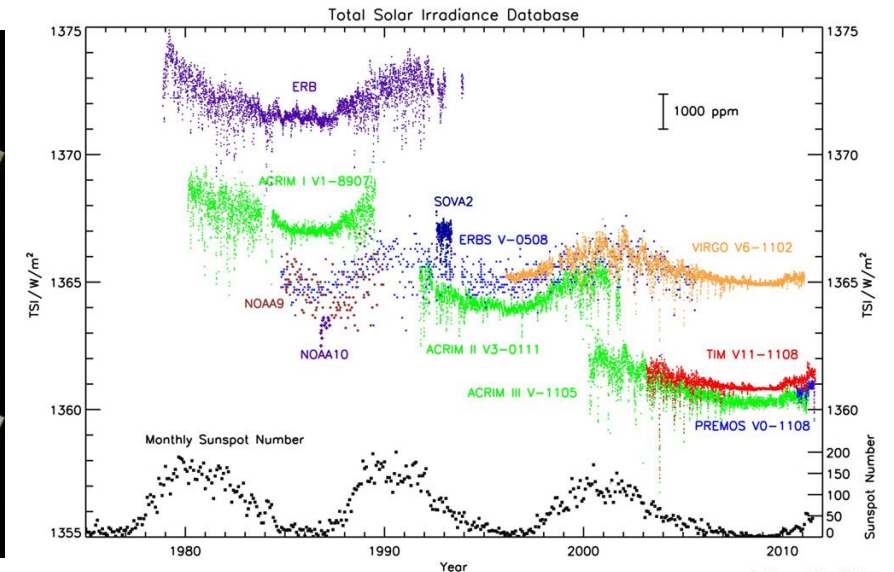
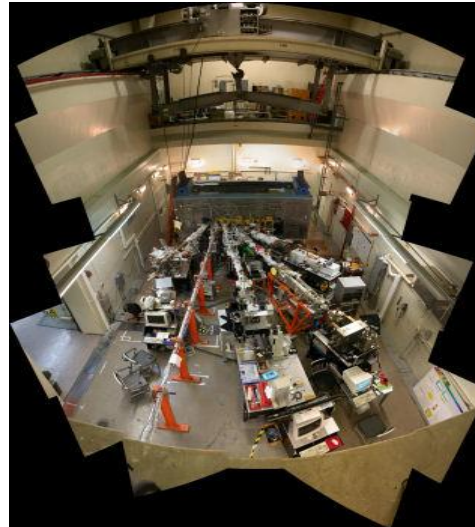
3-element systems (1 aperture)

Solar radiometry example

Multistage systems

Recent innovations

Summary



Some prior work diffraction effects in radiometry:

Theory:

Rayleigh (*Phil. Mag.* **11**, 214, 1881): Rayleigh formula $1 - J_0^2(v) - J_1^2(v)$

E. Lommel (*Abh. Bayer. Akad.* **15**, 233, 1885): Fresnel diffraction, unfocussed

E. Wolf (Proc. Roy. Soc. A **204**, 533, 1951)

J. Focke (*Optica Acta* **3**, 161, 1956)

Radiometry (mostly at NMIs):

C.L. Sanders and O.C. Jones (*J. Opt. Soc. Am.* **52**, 731, 1962)

N. Ooba (*J. Opt. Soc. Am.* **54**, 357, 1964)

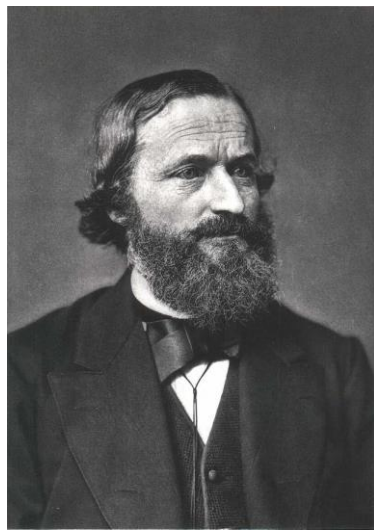
W.R. Blevin (*Metrologia* **6**, 39, 1970): effective-wavelength approximation

W.H. Steel, M. De, and J.A. Bell (*J. Opt. Soc. Am.* **62**, 1099, 1972): extended source

L.P. Boivin (*Appl. Opt.* **14**, 197; **14**, 2002; **15**, 1204, **16**, 377, 1972-1977): general

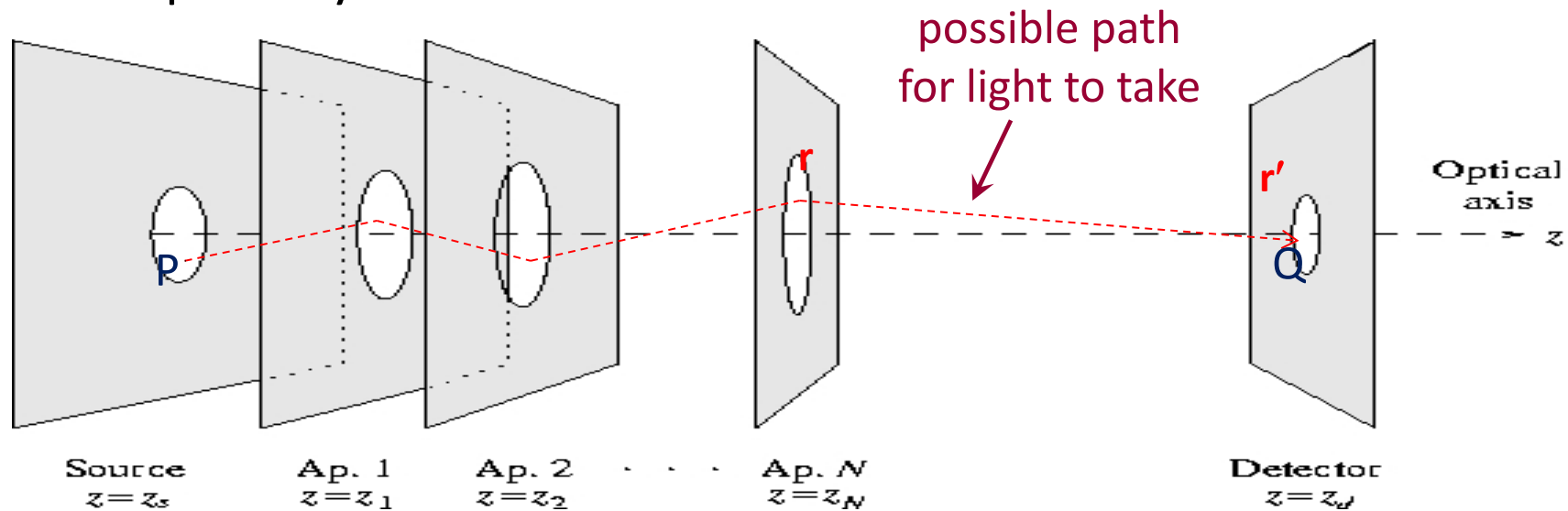
Physical optics: key approximations

- Scalar-wave approximation
- Kirchhoff diffraction theory, cont'd.
- Fresnel-paraxial (Gaussian optics) approx.



Gustav Kirchhoff

Consider this optical system:



Repeated application of approximations gives

$$u(\mathbf{Q}) = \frac{1}{(i\lambda)^N} \int_{A_1} dx_1 dy_1 \dots \int_{A_N} dx_N dy_N G(\mathbf{P}, \mathbf{x}_1) \dots G(\mathbf{x}_N, \mathbf{Q}) \cdot \exp[i\sum_k \delta l_k(\mathbf{x}_k)]$$

Allows for
focusing
effects

Identification of 3-element subsystems:

SAD subsystems:

SAD:
source-aperture-detector

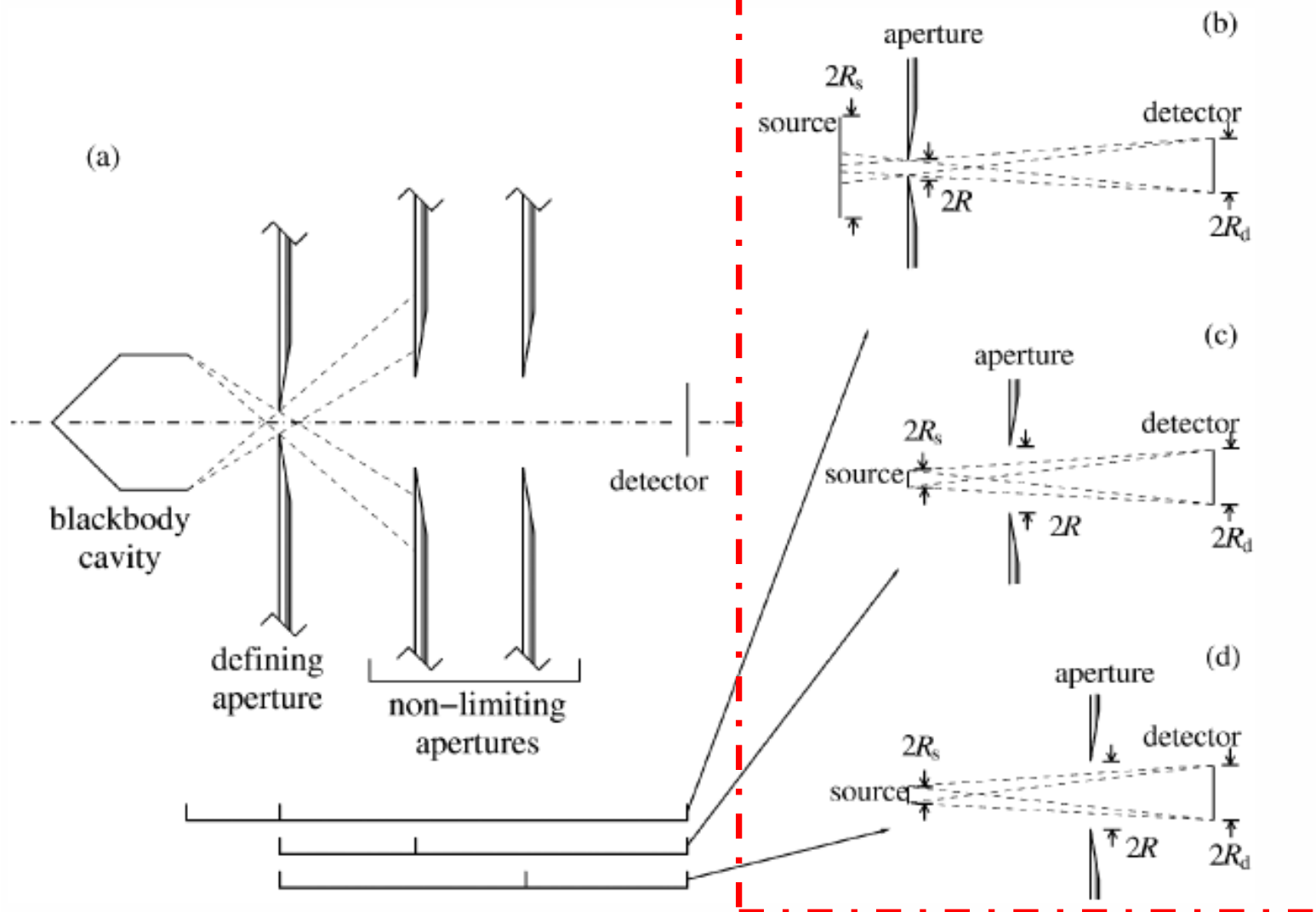


FIG. 9.7. Optical setup conceptually treated as three SAD setups for purposes of diffraction effects.

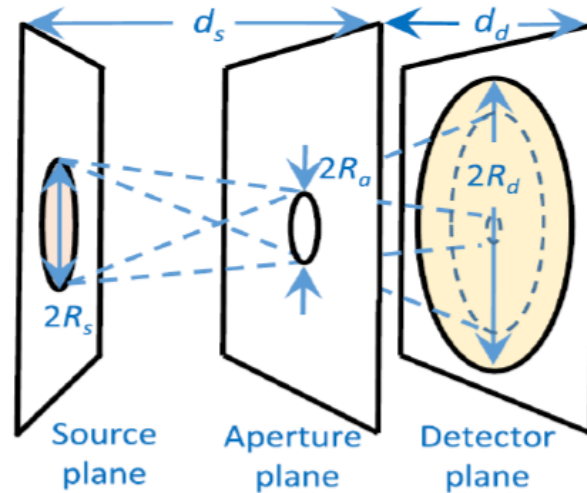
Diffraction Effect in SAD systems (point source)

$$L = \frac{\text{flux on detector}}{\text{flux on aperture}}$$

v, u, w (& A): depend on geometry, focusing power (& temperature)

Limiting geometries

$w^2 =$ geometrically
illuminated
fraction of
detector area



Spectral case:

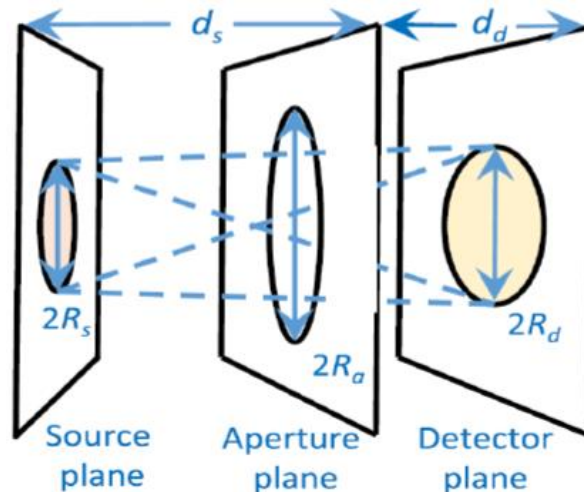
$$L = 1 - L_B(v, w)$$

Thermal case:

$$L = 1 - \frac{A^4}{6\zeta(4)} F_B(A, w)$$

Non-limiting geometries

$w^2 =$ geometrical
value of L



Spectral case:

$$\frac{L}{w^2} = 1 + L_B(v, w) - \frac{1}{w^2} L_X(v, w)$$

Thermal case:

$$\frac{L}{w^2} = 1 + \frac{A^4}{6\zeta(4)} \left[F_B(A, w) - \frac{1}{w^2} F_X(A, w) \right]$$

- **Integral representation of $L_B(v,w)$, $L_X(v,w)$, $F_B(A,w)$ and $F_X(A,w)$**
 - **asymptotic expansions** (large v , small A)
 - **exact evaluation by appropriate quadrature** (large v , small A)
 - generalizable to **extended sources**...

• **Sample asymptotic results for a point source:**

$$L_B(v, w) \sim \frac{1}{\pi} \left[\frac{2}{v(1-w^2)} - \frac{\cos(2v)}{v^2(1-w^2)} + \frac{1-20w^2-90w^4-20w^6+w^8}{4v^3(1-w^2)^5} - \frac{(1-18w^2+w^4)\sin(2v)}{4v^3(1-w^2)^5} + \dots \right]$$

$$F_B(A, w) \sim \frac{4\zeta(3)}{\pi(1-w^2)} A^{-3} - \left(\frac{1-20w^2-90w^4-20w^6+w^8}{4\pi(1-w^2)^5} \right) \left(A^{-1} \log_e A - \frac{2\gamma + 6\log_e 2 + 11/3}{2} A^{-1} \right) + \left[-\frac{5w^8-112w^6-586w^4-112w^2+5}{6\pi(1-w^2)^5} + \frac{32w^3(1+w^2)}{\pi(1-w^2)^5} \log_e \left(\frac{1+w}{1-w} \right) \right] A^{-1} + \dots$$

- Palindromic polynomials at **all orders**, as well as in $L_X(v,w)$ and $F_X(A,w)$.
- In particular, consider small- λ form for spectral power:

Limiting case:

$$\frac{\Phi_\lambda(\lambda)}{\Phi_\lambda^0(\lambda)} \approx 1 - \lambda a'_0(\lambda) - \lambda^{7/2} \{ a'_B(\lambda) + [a'_B(\lambda)]^* \}$$

Non-limiting case:

$$\frac{\Phi_\lambda(\lambda)}{\Phi_\lambda^0(\lambda)} \approx 1 + \lambda a_0(\lambda) + \lambda^{7/2} \{ a_B(\lambda) + [a_B(\lambda)]^* \} \\ + \lambda^3 \{ a_X(\lambda) + [a_X(\lambda)]^* \}$$

All a -functions involve trivial phase factors and smooth functions of λ , facilitating interpolation over wavelengths where integral representations are more practical than exact numerical evaluation!

Extended sources:

Generalizations of all previous results are also in hand.

General formula—

$$\Phi = C \int_{-1}^{+1} dx \frac{\{(1-x^2)[(2+\sigma x)^2 - \sigma^2]\}^{1/2}}{1+\sigma x} \int_0^\infty d\lambda L(u, v) L_\lambda(\lambda)$$

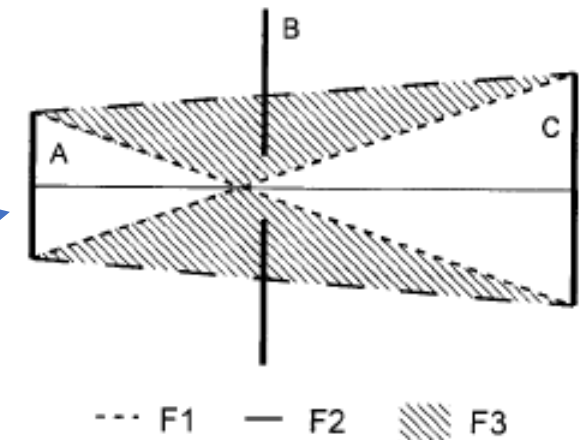
$$C = 4\pi^3 R_a^4 R_s^2 R_d^2 / (d_s^2 d_d^2 \alpha_0^2)^2 \quad (\text{depends on geometry})$$

W.H. Steel *et al.*, *J. Opt. Soc. Am.* **62**, 1099 (1972)

L.P. Boivin, *Appl. Opt.* **15**, 1204 (1976)

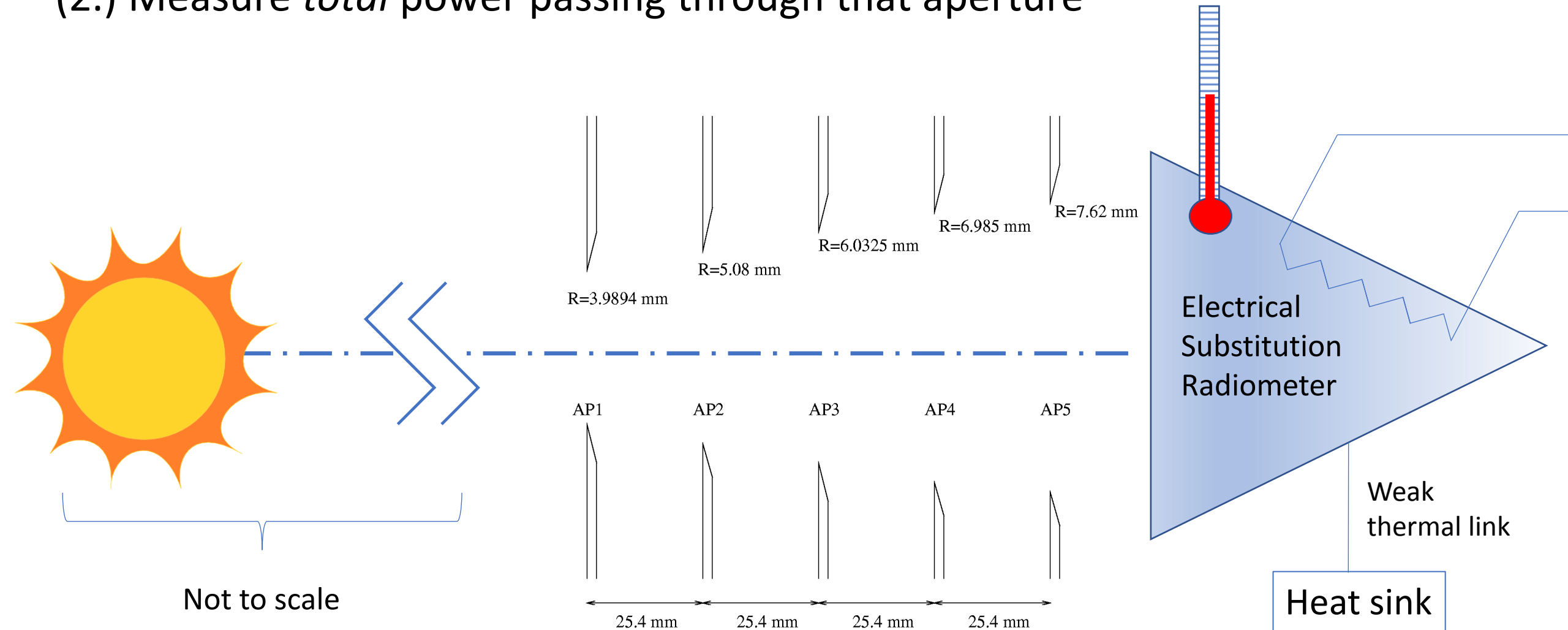
E.L. Shirley, *Appl. Opt.* **37**, 6581 (1998), *JOSA A* **21**, 1895 (2004);
JOSA A **33**, 1509 (2016)

P. Edwards and M. McCall,
Appl. Opt. **42**, 5024 (2003)—treats more geometries



Principle of measuring total solar irradiance:

- (1.) Have an aperture of known area
- (2.) Measure *total* power passing through that aperture



Sources of Differences in On-Orbital Total Solar Irradiance Measurements and Description of a Proposed Laboratory Intercomparison

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SAIC,

There is a 5 W/m^2 (about 0.35 %) difference between current on-orbit Total Solar Irradiance (TSI) measurements. On 18-20 July 2005, a workshop was held at the National Institute of Standards and Technology (NIST) in Gaithersburg, Maryland that focused on understanding possible reasons for this difference, through an examination of the instrument designs, calibration approaches, and appropriate measurement equations. The instruments studied in that workshop included the Active Cavity Radiometer Irradiance Monitor III (ACRIM III) on the Active Cavity Radiometer Irradiance Monitor SATellite (ACRIMSAT), the Total Irradiance Monitor (TIM) on the Solar Radiation and Climate Experiment (SORCE), the Variability of solar Irradiance and Gravity Oscillations (VIRGO) on the Solar and Heliospheric Observatory (SOHO), and the Earth

a session on laboratory-based comparisons and the application of new laboratory comparison techniques. The workshop has led to investigations of the effects of diffraction and of aperture area measurements on the differences between instruments. In addition, a laboratory-based instrument comparison is proposed that uses optical power measurements (with lasers that underfill the apertures of the TSI instruments), irradiance measurements (with lasers that overfill the apertures of the TSI instrument), and a cryogenic electrical substitution radiometer as a standard for comparing the instruments. A summary of the workshop and an overview of the proposed research efforts are presented here.

Key words: absolute radiometric calibration; diffraction calculations; total solar

Sources of Differences in On-Orbital Total Solar Irradiance Measurements and Description of a Proposed

IOP PUBLISHING

METROLOGIA

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Volume 113

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Total solar irradiance data record accuracy and consistency improvements

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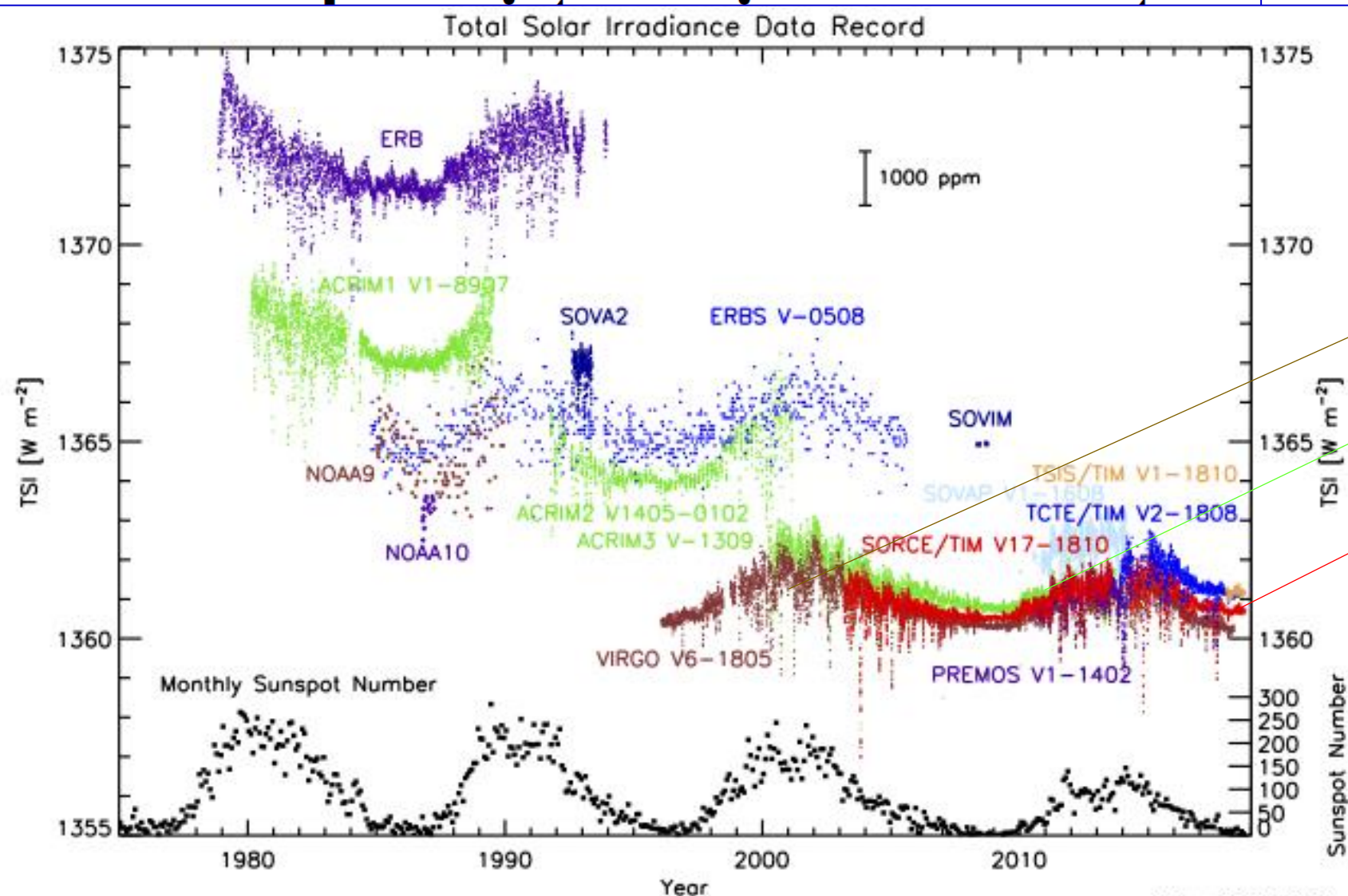
Radiation and Climate Experiment (SORCE), the Variability of solar Irradiance and Gravity Oscillations (VIRGO) on the Solar and Heliospheric Observatory (SOHO), and the Earth Radiation Budget Experiment (ERBE) on

are presented here.

Key words: absolute radiometric calibration; diffraction calculations; total solar irradiance (TSI); TSI uncertainty; TSI

Total solar irradiance data record

acc

Greg
Karl¹ Labora² Physik³ ACRIM

Corrected for
0.12% diffraction gain

Corrected for
0.16% diffraction gain

Corrected for
0.04% diffraction loss

**0.02% decadal
variation in TSI
relevant to
understanding
climate change!**

Application of algorithmic speedups to calculation of diffraction-corrected throughput of a multi-stage solar radiometer:



BEFORE FFT TRICK (also, using 10.0 GB memory):

```
0.9020000000000000E-03 0.7620000000000048E+01 0.317948922457192E-02 cap
47570.374u 12.473s 1:44:52.68 756.1% 0+0k 0+50624io 0pf+0w
```

AFTER FFT TRICK* (also, using 1.3 GB memory):

```
0.9020000000000000E-03 0.7620000000000048E+01 0.317948922456555E-02 cap
678.938u 1.529s 11:20.24 100.0% 0+0k 0+13744io 0pf+0w
```

* J.S. Rubin, *et al.*, *Appl. Opt.* **57**, 788 (2018)

Beyond the SAD paradigm:

- Multistage optics trains
- Vignetting effects

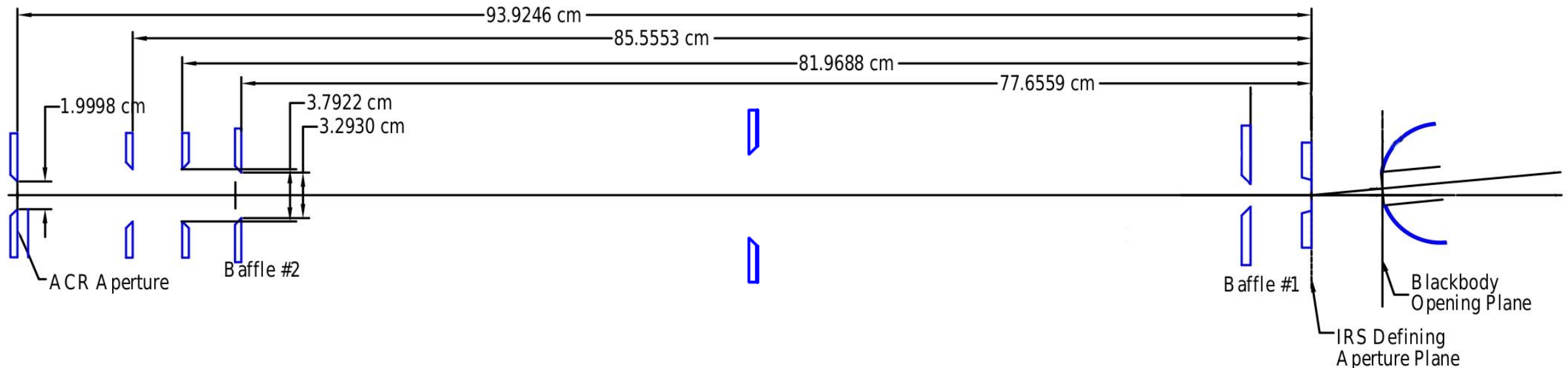
One-edge effects:

→ corrections proportional to λ or $1/T$.

Two-edge effects (most important for source-pinhole-baffle-detector cases):

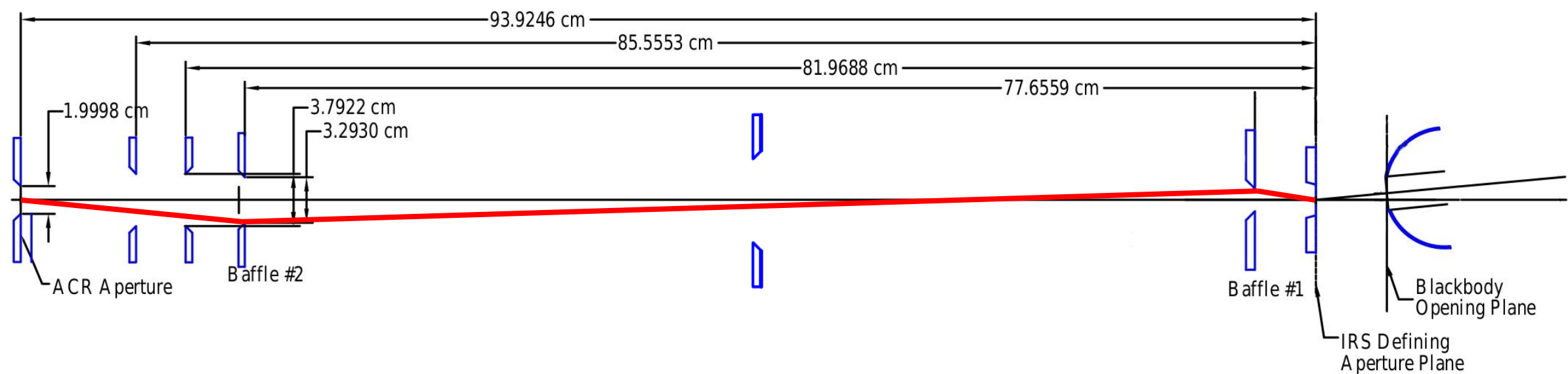
→ corrections proportional to λ^2 or $1/T^2$.

Example: blackbody calibration in NIST's Low-background infrared facility:

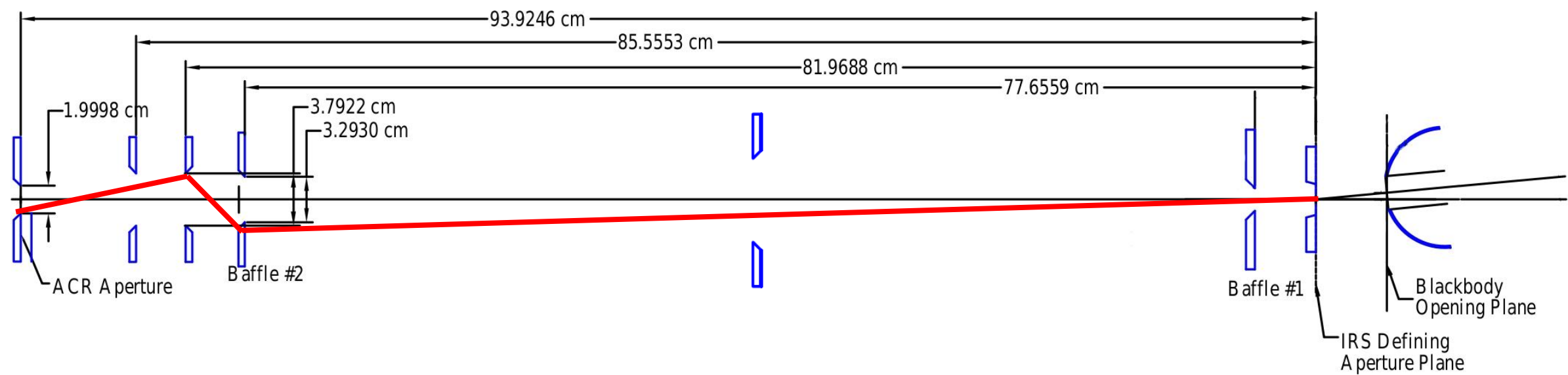


Some 3-element subsystems can be treated for total or spectral power diffraction effects efficiently. We are moving to treating other effects more **automatically**.

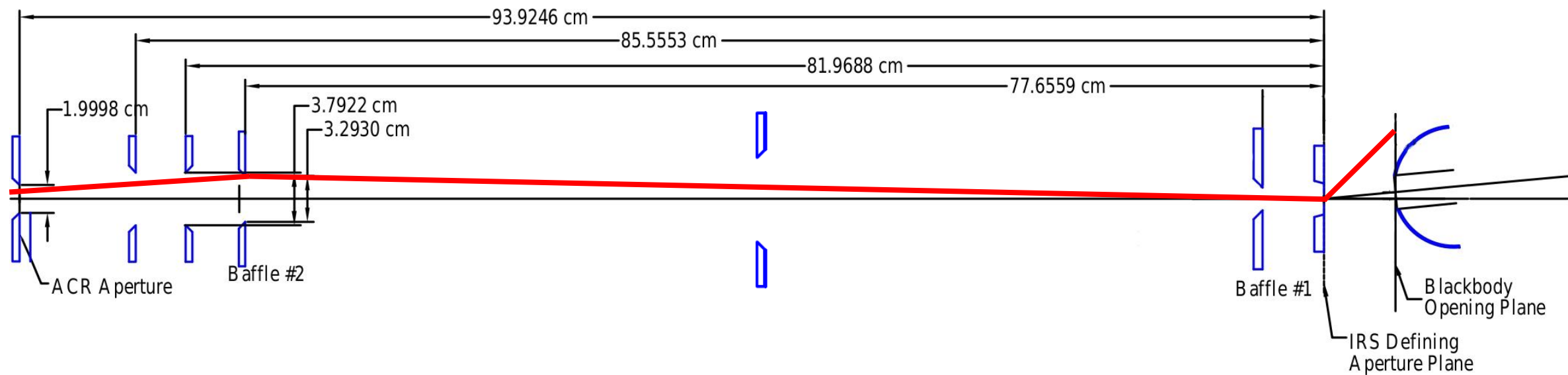
Light that is diffracted twice...



Light that is diffracted twice...2nd bounce might be on an aperture normally not illuminated

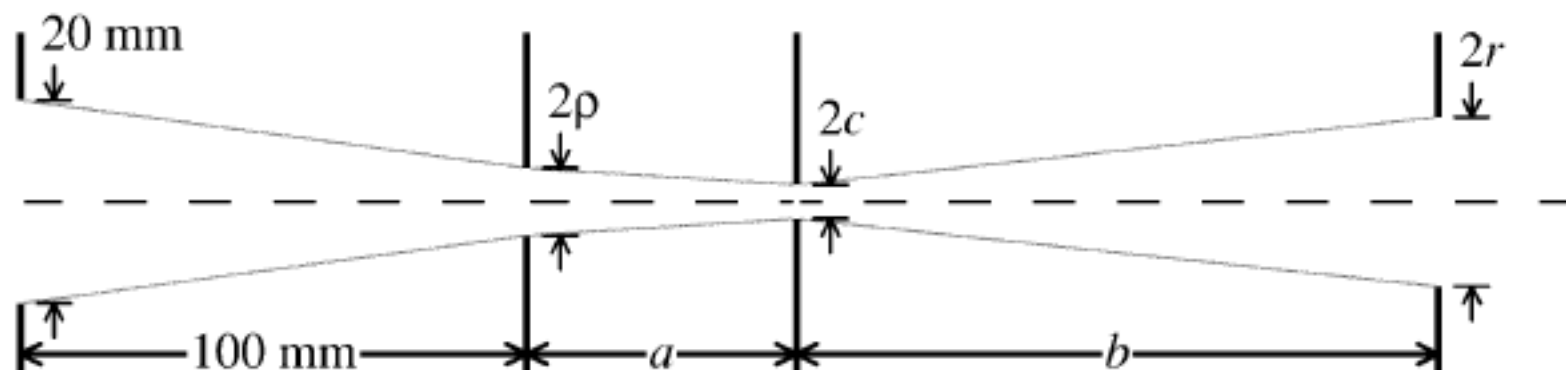


Light that should be diffracted 1x might be reduced by diffraction at BB pinhole aperture

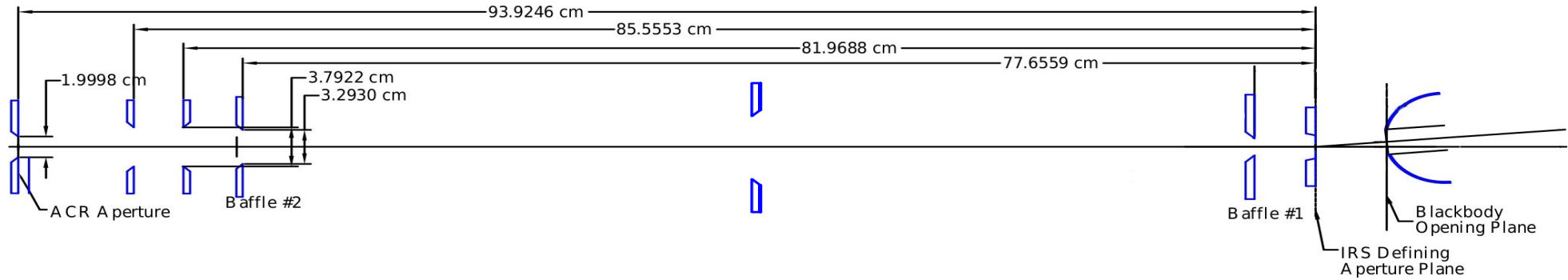


A baffle nominally not illuminated might diffract light after the pinhole diffracts it on the baffle edge...

In another context, having a blackbody recessed from the S of a SAD combination can also have a secondary effect



Treatment of a multi-stage system, in practice:



At small wavelength, one can show*

$$\frac{\Phi_{\lambda}(\lambda)}{\Phi_{0,\lambda}(\lambda)} = 1 + a_1\lambda + a_2\lambda^2 + R_{\lambda}(\lambda)$$

$(a_1, a_2) = \text{analytic}$

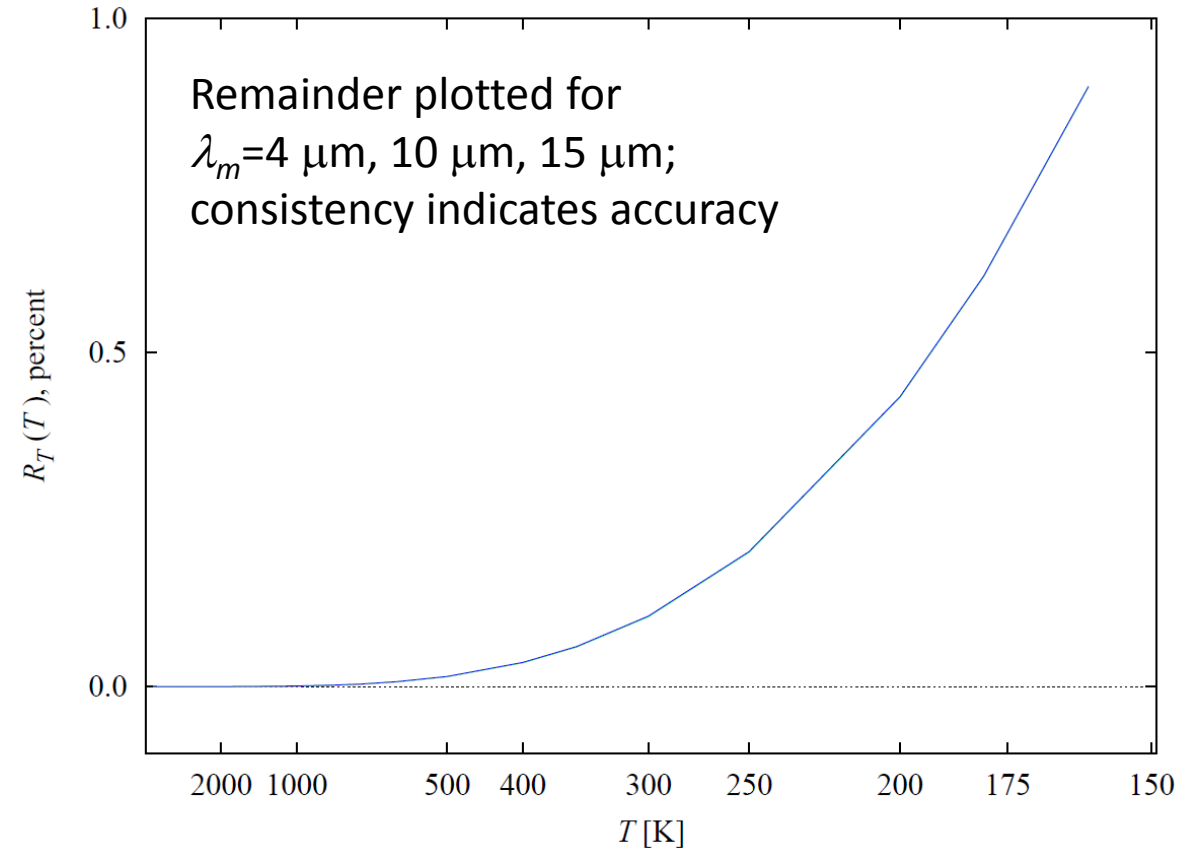
$$R_{\lambda}(\lambda) = \begin{cases} \text{neglected for } \lambda < \lambda_m \\ \text{computed for } \lambda \geq \lambda_m \end{cases}$$

At high temperature, one can show*

$$\frac{\Phi}{\Phi_0} = 1 + \frac{b_1}{T} + \frac{b_2}{T^2} + R_T(T)$$

$(b_1, b_2) = \text{analytic}$

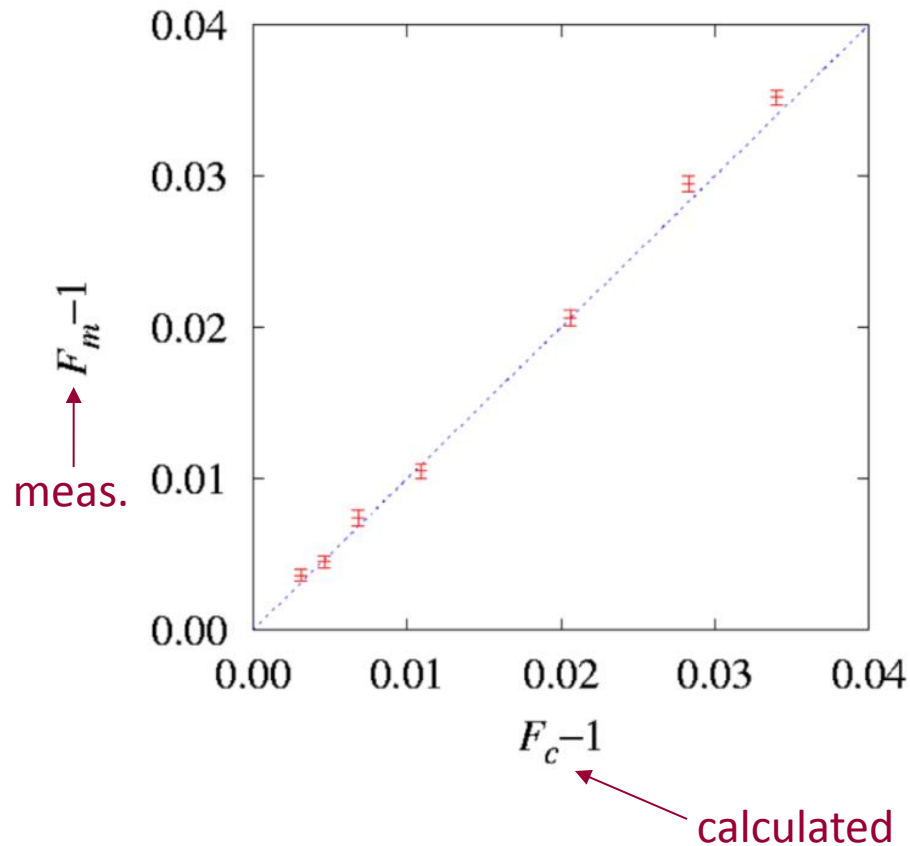
$$R_T(T) \sim \frac{b_3}{T^3} \text{ at large } T \text{ (usually)}$$



*Based on an extended boundary-diffraction-wave formulation; E. L. Shirley, J. Mod. Opt. 54, 515 (2007)

Comparison of measured and calculated diffraction effects:

L.P. Boivin,
(*Appl. Opt.*
17, 3323,
1978)



Statistical analysis suggests
~2 % systematic error in calculated
diffraction corrections.

Effect of tothing of aperture:

- reduction in diffraction effect because of phase cancellations in $u_{BDW}(r_d)$.

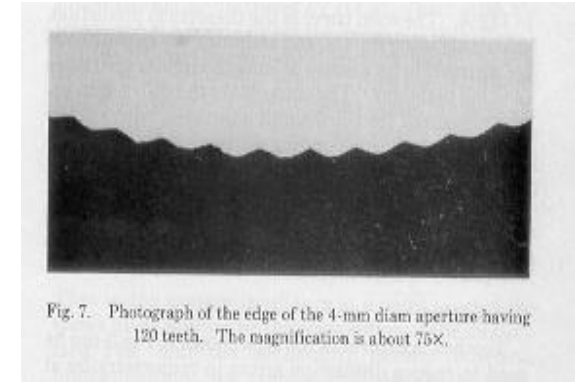
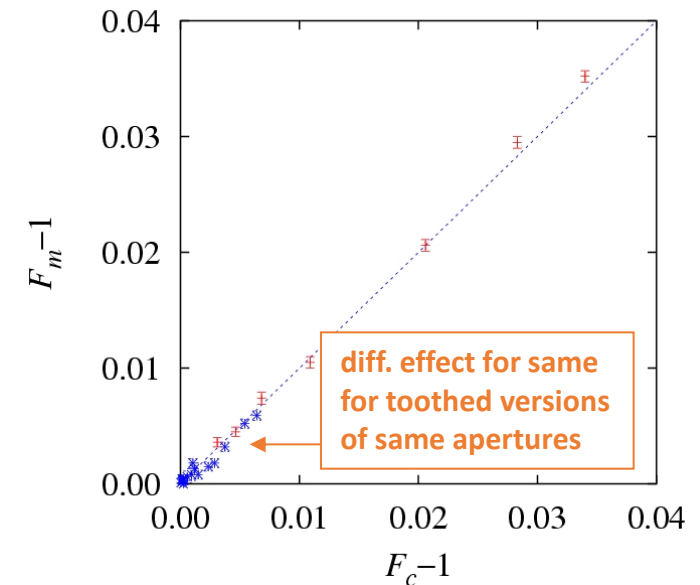


Fig. 7. Photograph of the edge of the 4-mm diam aperture having 120 teeth. The magnification is about 75%.



Summary of results:

- Diffraction affects radiometry
- Largely understood
- Much work has been done
- We have programs that are efficient and pull out asymptotic trends, easing or obviating calculations
- Codes are ever more efficient, and are available